Silicon N/P Channel MOS FET High Speed Power Switching

HITACHI

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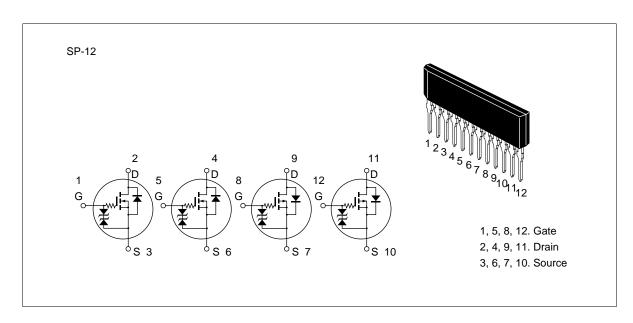
Features

• Low on-resistance

$$\begin{split} & \text{N Channel:} & \quad R_{\text{DS(on)}} \leq & 0.17 \,\, \Omega, \, V_{\text{GS}} = 10 \,\, \text{V}, \, I_{\text{D}} = 4 \,\, \text{A} \\ & \text{P Channel:} & \quad R_{\text{DS(on)}} \leq & 0.2 \,\, \Omega, \, V_{\text{GS}} = -10 \,\, \text{V}, \, I_{\text{D}} = -4 \,\, \text{A} \end{split}$$

- 4 V gate drive devices.
- High density mounting

Outline





Absolute Maximum Ratings ($Ta = 25^{\circ}C$)

Item	Symbol	Ratin	gs	Unit
		Nch	Pch	
Drain to source voltage	V _{DSS}	60	-60	V
Gate to source voltage	$V_{\sf GSS}$	±20	±20	V
Drain current	I _D	8	-8	A
Drain peak current	Note1 D(pulse)	32	-32	A
Body-drain diode reverse drain current	I _{DR}	8	-8	А
Channel dissipation	Pch (Tc = 25° C) Note2		28	W
Channel dissipation	Pch Note2		4.0	W
Channel temperature	Tch		150	°C
Storage temperature	Tstg		-55 to +150	°C

Note: 1. PW \leq 10 μ s, duty cycle \leq 1%

2. 4 devices operation

Electrical Characteristics (Ta = 25°C)

(N Channel)

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain to source breakdown voltage	V _{(BR)DSS}	60	_	_	V	$I_D = 10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	V _{(BR)GSS}	±20	_	_	V	$I_{G} = \pm 100 \ \mu A, \ V_{DS} = 0$
Gate to source leak current	I _{GSS}	_	_	±10	μΑ	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I _{DSS}	_	_	250	μΑ	$V_{DS} = 50 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	1.0	_	2.5	V	$V_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA}$
Static drain to source on state	R _{DS(on)}	_	0.13	0.17	Ω	$I_D = 4 \text{ A}, V_{GS} = 10 \text{ V}^{\text{Note3}}$
resistance	R _{DS(on)}	_	0.19	0.24	Ω	$I_D = 4 \text{ A}, V_{GS} = 4 \text{ V}^{\text{Note3}}$
Forward transfer admittance	y _{fs}	3.5	5.5	_	S	$I_D = 4 \text{ A}, V_{DS} = 10 \text{ V}^{\text{Note3}}$
Input capacitance	Ciss	_	33	_	pF	V _{DS} = 10 V
Output capacitance	Coss	_	220	_	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	_	5.2	_	pF	f = 1 MHz
Gate series resistance	Rg	_	1.5	_	kΩ	$V_{DS} = 10 \text{ V}, V_{GS} = 0$ f = 1 MHz
Turn-on delay time	t _{d(on)}	_	0.15	_	ns	V _{GS} = 10 V, I _D = 4 A
Rise time	t _r	_	0.5	_	ns	$R_L = 7.5 \Omega$
Turn-off delay time	t _{d(off)}	_	3.2	_	ns	_
Fall time	t _f	_	1.4	_	ns	_
Body-drain diode forward voltage	V_{DF}	_	1.5	_	V	I _F = 8 A, V _{GS} = 0
Body-drain diode reverse recovery time	t _{rr}		850	_	ns	$I_F = 8 \text{ A}, V_{GS} = 0$ diF/ dt = 50 A/ μ s

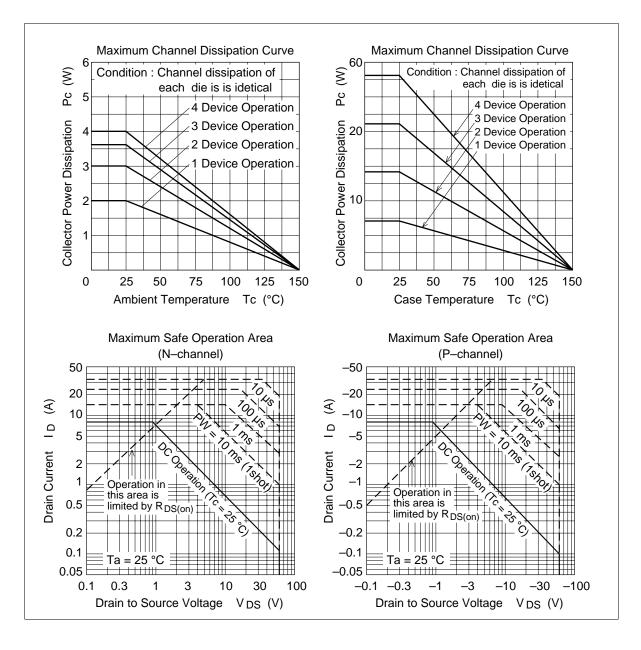
Note: 3. Pulse test

(P Channel)

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain to source breakdown voltage	$V_{(BR)DSS}$	-60	_	_	V	$I_{D} = -10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS}$	±20	_	_	V	$I_G = \pm 100 \ \mu A, \ V_{DS} = 0$
Gate to source leak current	I _{GSS}	_	_	±10	μΑ	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I _{DSS}	_	_	-250	μΑ	$V_{DS} = -50 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	$V_{\text{GS(off)}}$	-1.0	_	-2.5	V	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ mA}$
Static drain to source on state	R _{DS(on)}	_	0.15	0.2	Ω	$I_D = -4 \text{ A}, V_{GS} = -10 \text{ V}^{\text{Note3}}$
resistance	R _{DS(on)}	_	0.2	0.27	Ω	$I_D = -4 \text{ A}, V_{GS} = -4 \text{ V}^{\text{Note3}}$
Forward transfer admittance	y _{fs}	3.5	6.0	_	S	$I_D = -4 \text{ A}, V_{DS} = -10 \text{ V}^{\text{Note3}}$
Input capacitance	Ciss	_	17	_	pF	V _{DS} = -10 V
Output capacitance	Coss	_	460	_	pF	$V_{GS} = 0$
Reverse transfer capacitance	Crss	_	1.2	_	pF	f = 1 MHz
Gate series resistance	Rg	_	3.2	_	kΩ	$V_{DS} = 0$, $V_{GS} = 0$ f = 1 MHz
Turn-on delay time	t _{d(on)}	_	0.6	_	ns	$V_{GS} = -10 \text{ V}, I_{D} = -4 \text{ A}$
Rise time	t _r	_	2.1	_	ns	$R_L = 7.5 \Omega$
Turn-off delay time	t _{d(off)}	_	12	_	ns	
Fall time	t _f	_	5.8	_	ns	
Body-drain diode forward voltage	V_{DF}	_	-1.2	_	V	$I_F = -8 \text{ A}, V_{GS} = 0$
Body-drain diode reverse recovery time	t _{rr}	_	2.5	_	ns	$I_F = -8 \text{ A}, V_{GS} = 0$ diF/ dt = 50 A/ μ s

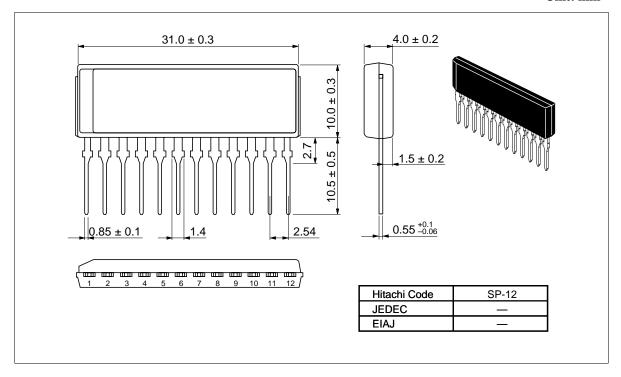
Note: 3. Pulse test

Main Characteristics



Package Dimensions

Unit: mm



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